

## UNISONIC TECHNOLOGIES CO., LTD

### UT100N07H

#### **Preliminary**

#### **Power MOSFET**

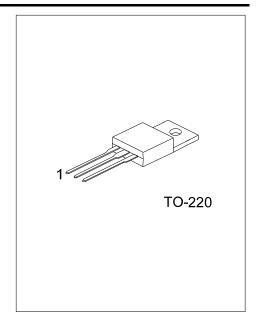
# 100A, 70V N-CHANNEL POWER MOSFET

#### ■ DESCRIPTION

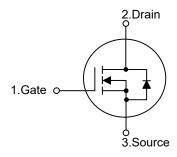
The UTC **UT100N07H** is an N-channel enhancement mode Power FET, it uses UTC's advanced technology to provide customers a minimum on-state resistance and high switching speed.

#### ■ FEATURES

- \*  $R_{DS(ON)} \le 7.0 \text{ m}\Omega$  @  $V_{GS}=10V$ ,  $I_{D}=50A$
- \* High switching speed
- \* Improved dv/dt capability



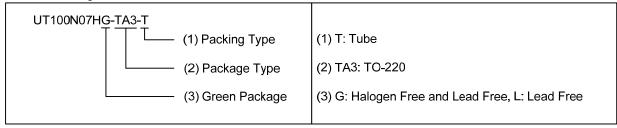
#### ■ SYMBOL



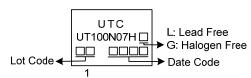
#### ■ ORDERING INFORMATION

Ordering Number		Daalaaaa	Pin Assignment			D. alain a	
Lead Free	Halogen Free	Package	1	2	3	Packing	
UT100N07HL-TA3-T	UT100N07HG-TA3-T	TO-220	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



#### MARKING



www.unisonic.com.tw 1 of 5

#### ■ ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub>=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V <sub>DSS</sub>	70	V	
Gate-Source Voltage		V <sub>GSS</sub>	±20	V	
Drain Current	Continuous	I <sub>D</sub>	100	Α	
	Pulsed	I <sub>DM</sub> 200		Α	
Avalanche Energy	Single Pulsed	Eas	125	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	2.5	V/ns	
Power Dissipation		P <sub>D</sub>	200	W	
Junction Temperature		TJ	+150	°C	
Storage Temperature Range		Tstg	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 0.1mH,  $I_{AS}$  = 50A,  $V_{DD}$  = 30V,  $R_G$  = 25 $\Omega$ , Starting  $T_J$  = 25 $^{\circ}$ C
- 4. IsD  $\leq$  30A, di/dt  $\leq$  200A/ $\mu$ s, VDD  $\leq$  BVDSS, Starting TJ = 25°C

#### ■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θЈА	62.5	°C/W	
Junction to Case	θјс	0.625	°C/W	

#### ■ ELECTRICAL CHARACTER ISTICS (T<sub>J</sub>=25°C, unless otherwise specified)

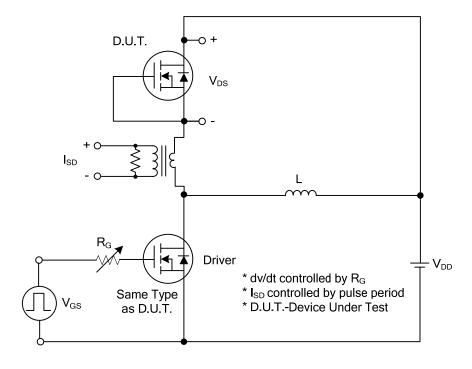
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS		-		ā.	-		_
Drain-Source Breakdown Voltage		BV <sub>DSS</sub>	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	70			V
Drain-Source Leakage Current		I <sub>DSS</sub>	V <sub>DS</sub> =70V,V <sub>GS</sub> =0V			1	μΑ
Gate-Source Leakage Current	Forward	loop	V <sub>GS</sub> =+20V, V <sub>DS</sub> =0V			+100	nA
	Reverse	Igss	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	I <sub>D</sub> =250μA, V <sub>DS</sub> =V <sub>GS</sub>	2.0		4.0	V
Static Drain-Source On-State Resistance		R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =50A			7.0	mΩ
DYNAMIC PARAMETERS							
Input Capacitance		C <sub>ISS</sub>			14300		рF
Output Capacitance		Coss	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1MHz		1460		рF
Reverse Transfer Capacitance		Crss			1270		рF
SWITCHING PARAMETERS							
Total Gate Charge		Q <sub>G</sub>	\/F6\/\/10\/\100A		145		nC
Gate to Source Charge		Q <sub>G</sub> s	V <sub>DD</sub> =56V, V <sub>GS</sub> =10V, I <sub>D</sub> =100A, (Note 1, 2)		40		nC
Gate to Drain Charge		$Q_{GD}$	(1006 1, 2)		60		nC
Turn-ON Delay Time		$t_{D(ON)}$			18		ns
Rise Time		t <sub>R</sub>	V <sub>DD</sub> =35V, V <sub>GS</sub> =10V I <sub>D</sub> =100A,		19		ns
Turn-OFF Delay Time		t <sub>D(OFF)</sub>	R <sub>G</sub> =3Ω (Note 1, 2)		34		ns
Fall-Time		t⊧			20		ns
SOURCE- DRAIN DIODE RATII	NGS AND C	CHARACTER	RISTICS				
Maximum Body-Diode Continuous Current		Is				100	Α
Maximum Body-Diode Pulsed Current		Ism				200	Α
Drain-Source Diode Forward Voltage		V <sub>SD</sub>	Is=100A			1.4	V
Reverse Recovery Time		t <sub>rr</sub>	I <sub>S</sub> =30A, V <sub>GS</sub> =0V		60		nS
Reverse Recovery Charge (Note 1)		$Q_{rr}$	dl <sub>F</sub> /dt=100A/μs		105		nC

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%.

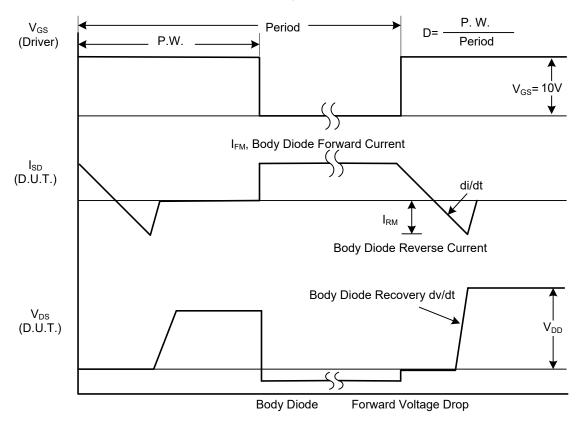
2. Essentially independent of operating ambient temperature.



#### ■ TEST CIRCUITS AND WAVEFORMS

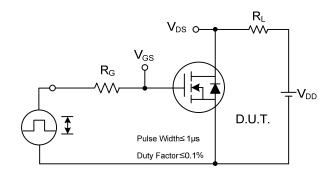


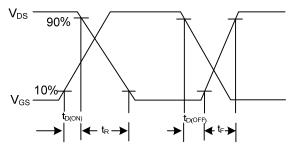
#### Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

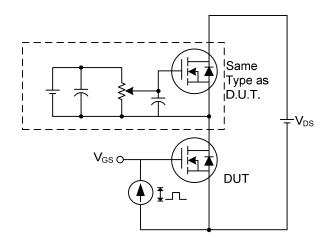
#### ■ TEST CIRCUITS AND WAVEFORMS

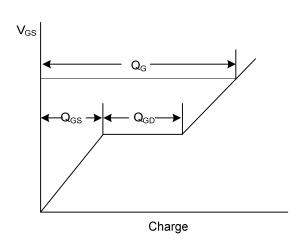




**Switching Test Circuit** 

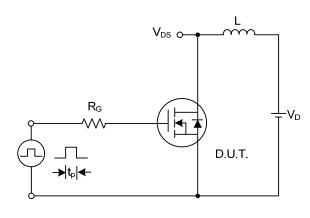
**Switching Waveforms** 

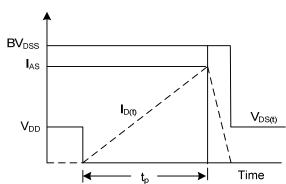




**Gate Charge Test Circuit** 

**Gate Charge Waveform** 





**Unclamped Inductive Switching Test Circuit** 

**Unclamped Inductive Switching Waveforms** 

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